



Certificate for RoHS Compliant Products

Bourns, Inc. certifies, as of this date, the products listed below (“Products”) are designated as conforming to the requirements of the European Union’s Restrictions on use of Certain Hazardous Substances in Electrical and Electronic Equipment Directive, 2002/95/EC (commonly called “RoHS”) and amendments and 2011/65/EU (commonly called “RoHS Recast”).

The information presented is based on Bourns’ understanding of the RoHS directive and Bourns’ knowledge of the materials that are used in the Products as of the date of disclosure, which, in some cases, is based on information provided by third parties.

Resistor Networks series: 4416P-LF, 4420P-LF

| Restricted Substances | RoHS Maximum Concentration Value (ppm)* |
|---|---|
| Cadmium (Cd) | 100 |
| Lead (Pb) | 1,000 |
| Mercury (Hg) | 1,000 |
| Hexavalent Chromium (Cr ⁺⁶) | 1,000 |
| Polybrominated biphenyls (PBB) | 1,000 |
| Polybrominated diphenyl ethers (PBDE) | 1,000 |

* Maximum limit does not apply to applications covered by RoHS exemptions. Maximum Concentration Values are based on homogeneous materials as defined in the RoHS Directive.

Exemptions used (if box is checked):

- 6a. Lead as an alloying element in steel containing up to 0.35% lead by weight
- 6b. Lead as an alloying element in aluminum containing up to 0.4% lead by weight
- 6c. Lead as an alloying element as a copper alloy containing up to 4% lead by weight.
- 7a. Lead in high melting temperature type solders (i.e., lead-based alloys containing more than 85% by weight or more lead).
- 7(c)-I. Electrical & electronic components containing lead in a glass or ceramic other than dielectric ceramic in capacitors.
- 34. Lead in cermet-based trimmer potentiometer elements.

Signature



Wil Cantrell

Date:

November 1, 2012

44xxP

General Information: The information provided herein is to the best of Bourns, Inc. knowledge and belief. To the extent that Bourns is relying on information provided by third parties, Bourns makes no warranty as to the accuracy or completeness of such information.